

# MDIS4N65B

## N-Channel MOSFET 650V, 3.65A, 2.2Ω

### General Description

These N-channel MOSFET are produced using advanced MagnaChip's MOSFET Technology, which provides low on-state resistance, high switching performance and excellent quality.

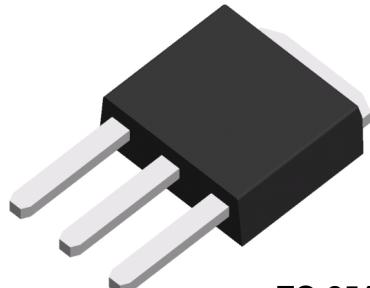
These devices are suitable device for SMPS, high Speed switching and general purpose applications.

### Features

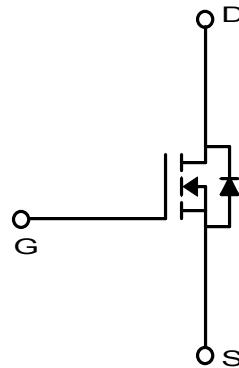
- $V_{DS} = 650V$
- $I_D = 3.65A$  @  $V_{GS} = 10V$
- $R_{DS(ON)} \leq 2.2\Omega$  @  $V_{GS} = 10V$

### Applications

- Power Supply
- PFC
- High Current, High Speed Switching



**TO-251-VS  
(IPAK-VS)**



### Absolute Maximum Ratings ( $T_a = 25^\circ C$ )

Characteristics	Symbol	Rating	Unit
Drain-Source Voltage	$V_{DSS}$	650	V
Gate-Source Voltage	$V_{GSS}$	$\pm 30$	V
Continuous Drain Current	$I_D$	3.65	A
		2.3	A
Pulsed Drain Current <sup>(1)</sup>	$I_{DM}$	14.6	A
Power Dissipation	$P_D$	68.3	W
		0.54	W/ $^\circ C$
Repetitive Avalanche Energy <sup>(1)</sup>	$E_{AR}$	6.83	mJ
Peak Diode Recovery $dv/dt$ <sup>(3)</sup>	$dv/dt$	4.5	V/ns
Single Pulse Avalanche Energy <sup>(4)</sup>	$E_{AS}$	170	mJ
Junction and Storage Temperature Range	$T_J, T_{stg}$	-55~150	$^\circ C$

### Thermal Characteristics

Characteristics	Symbol	MDIS4N65B	Unit
Thermal Resistance, Junction-to-Ambient <sup>(1)</sup>	$R_{\theta JA}$	110	$^\circ C/W$
Thermal Resistance, Junction-to-Case <sup>(1)</sup>	$R_{\theta JC}$	1.83	

## Ordering Information

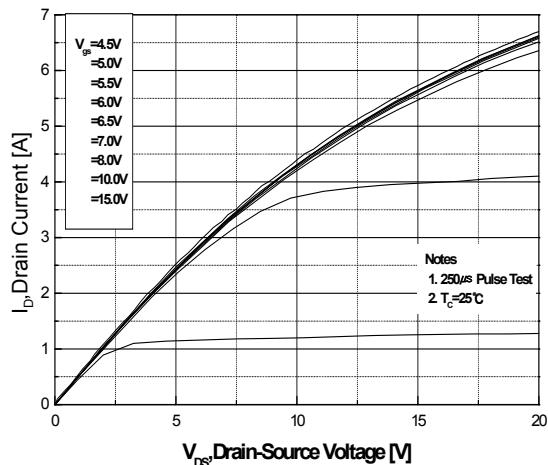
Part Number	Temp. Range	Package	Packing	RoHS Status
MDIS4N65BTH	-55~150°C	TO-251-VS (IPAK-VS)	Tube	Halogen Free

## Electrical Characteristics (Ta =25°C)

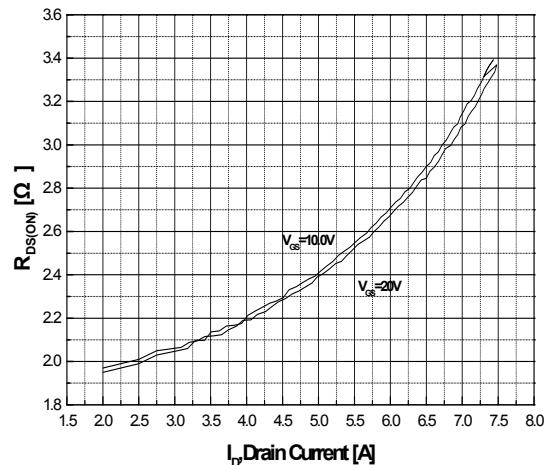
Characteristics	Symbol	Test Condition	Min	Typ	Max	Unit
<b>Static Characteristics</b>						
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	I <sub>D</sub> = 250μA, V <sub>GS</sub> = 0V	650	-	-	V
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA	2.0	-	4.0	
Drain Cut-Off Current	I <sub>DSS</sub>	V <sub>DS</sub> = 650V, V <sub>GS</sub> = 0V	-	-	1	μA
Gate Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> = ±30V, V <sub>DS</sub> = 0V	-	-	100	nA
Drain-Source ON Resistance	R <sub>D(S)ON</sub>	V <sub>GS</sub> = 10V, I <sub>D</sub> = 1.825A		1.8	2.2	Ω
Forward Transconductance	g <sub>f</sub>	V <sub>DS</sub> = 30V, I <sub>D</sub> = 1.825A	-	3.0	-	S
<b>Dynamic Characteristics</b>						
Total Gate Charge	Q <sub>g</sub>	V <sub>DS</sub> = 520V, I <sub>D</sub> = 4.0A, V <sub>GS</sub> = 10V	-	11.6	-	nC
Gate-Source Charge	Q <sub>gs</sub>		-	2.3	-	
Gate-Drain Charge	Q <sub>gd</sub>		-	4.6	-	
Input Capacitance	C <sub>iss</sub>	V <sub>DS</sub> = 25V, V <sub>GS</sub> = 0V, f = 1.0MHz	-	518	-	pF
Reverse Transfer Capacitance	C <sub>rss</sub>		-	3	-	
Output Capacitance	C <sub>oss</sub>		-	61	-	
Turn-On Delay Time	t <sub>d(on)</sub>	V <sub>GS</sub> = 10V, V <sub>DS</sub> = 325V, I <sub>D</sub> = 4.0A, R <sub>G</sub> = 25Ω	-	13	-	ns
Rise Time	t <sub>r</sub>		-	22	-	
Turn-Off Delay Time	t <sub>d(off)</sub>		-	41	-	
Fall Time	t <sub>f</sub>		-	25	-	
<b>Drain-Source Body Diode Characteristics</b>						
Maximum Continuous Drain to Source Diode Forward Current	I <sub>S</sub>	I <sub>S</sub> = 4.0A, V <sub>GS</sub> = 0V	-	-	3.65	A
Source-Drain Diode Forward Voltage	V <sub>SD</sub>		-	-	1.4	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>	I <sub>F</sub> = 4.0A, di/dt = 100A/μs	-	245	-	ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>		-	1.5	-	μC

Note :

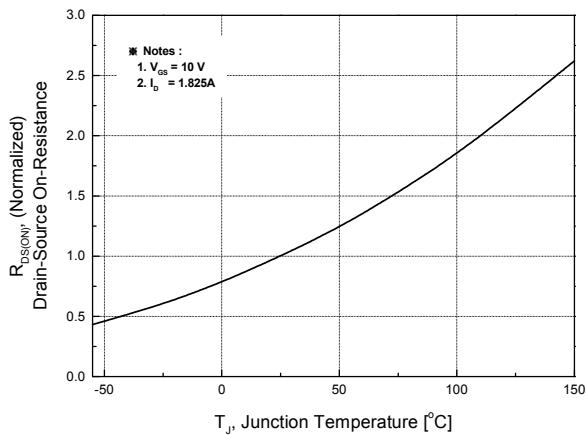
1. Pulse width is based on R<sub>esJC</sub> & R<sub>esJA</sub>, and the maximum allowed junction temperature of 150°C.
2. Pulse test: pulse width ≤300us, duty cycle≤2%, pulse width limited by junction temperature T<sub>J(MAX)</sub>=150°C.
3. I<sub>SD</sub> ≤3.65A, di/dt≤200A/us, V<sub>DD</sub>≤BVDSS, Starting T<sub>j</sub>=25°C
4. L=23.6mH, I<sub>AS</sub>=3.65A, V<sub>DD</sub>=50V, R<sub>g</sub> =25Ω, Starting T<sub>j</sub>=25°C,



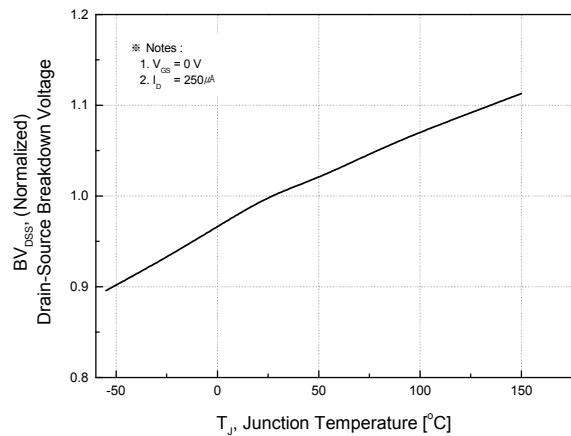
**Fig.1 On-Region Characteristics**



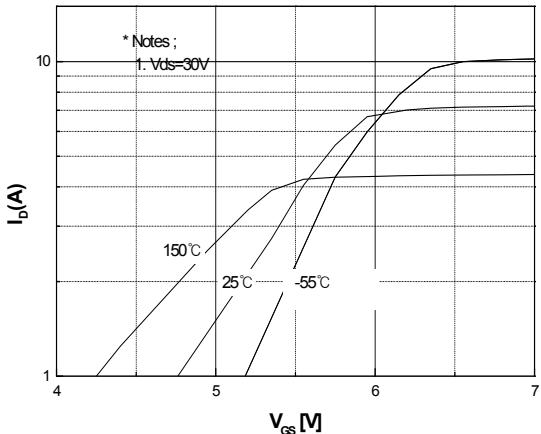
**Fig.2 On-Resistance Variation with Drain Current and Gate Voltage**



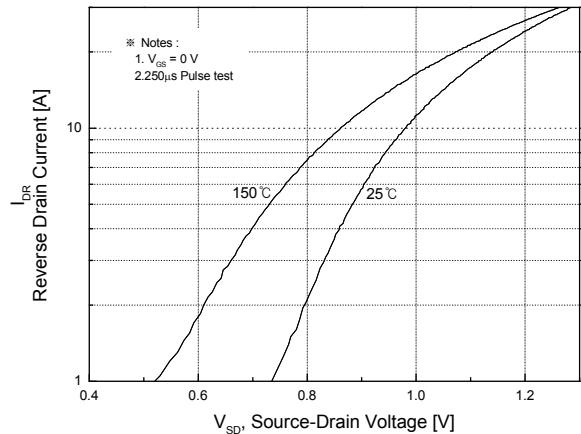
**Fig.3 On-Resistance Variation with Temperature**



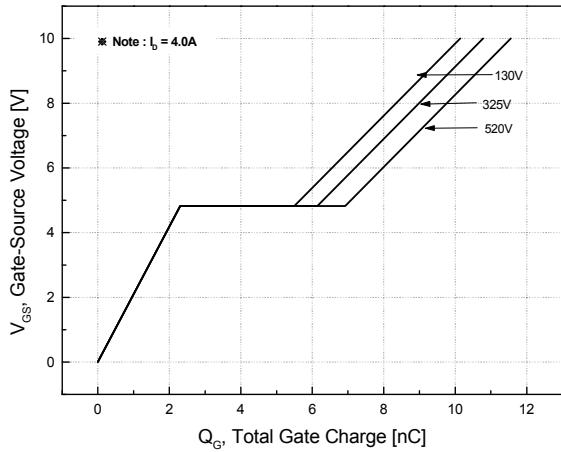
**Fig.4 Breakdown Voltage Variation vs. Temperature**



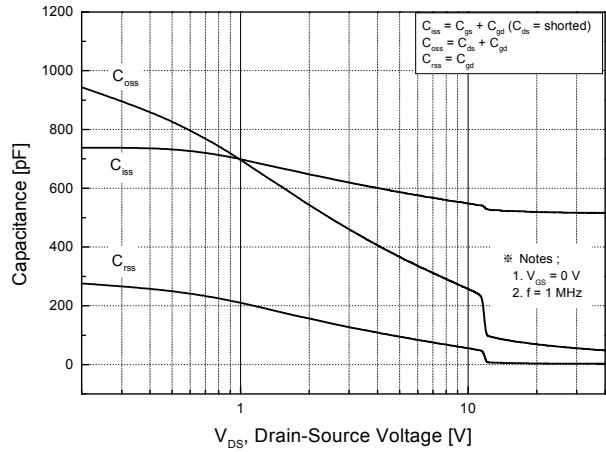
**Fig.5 Transfer Characteristics**



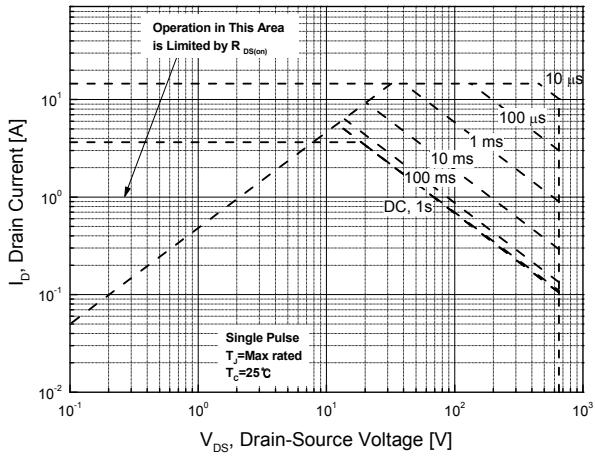
**Fig.6 Body Diode Forward Voltage Variation with Source Current and Temperature**



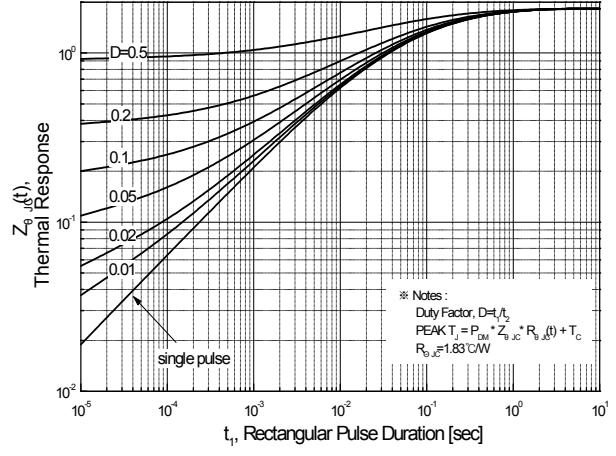
**Fig.7 Gate Charge Characteristics**



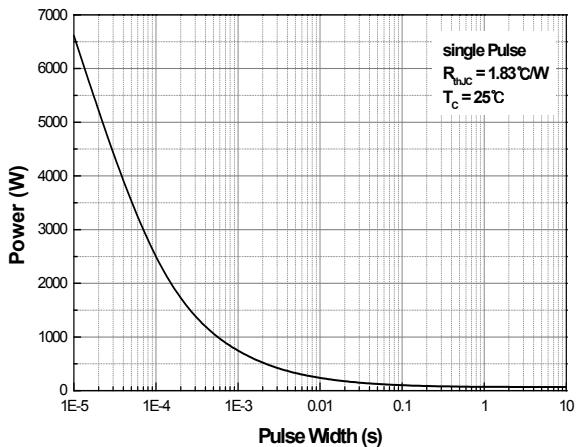
**Fig.8 Capacitance Characteristics**



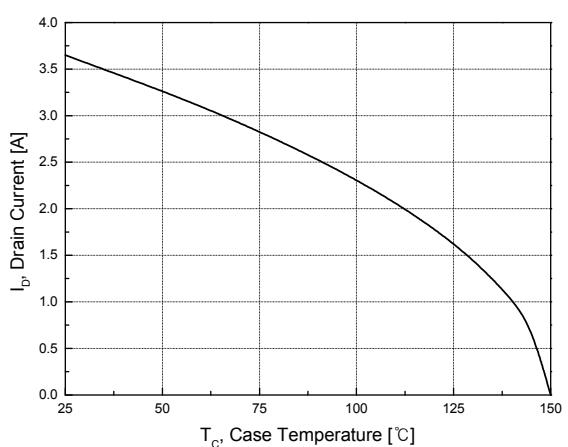
**Fig.9 Maximum Safe Operating Area**



**Fig.10 Transient Thermal Response Curve**



**Fig.11 Single Pulse Maximum Power Dissipation**

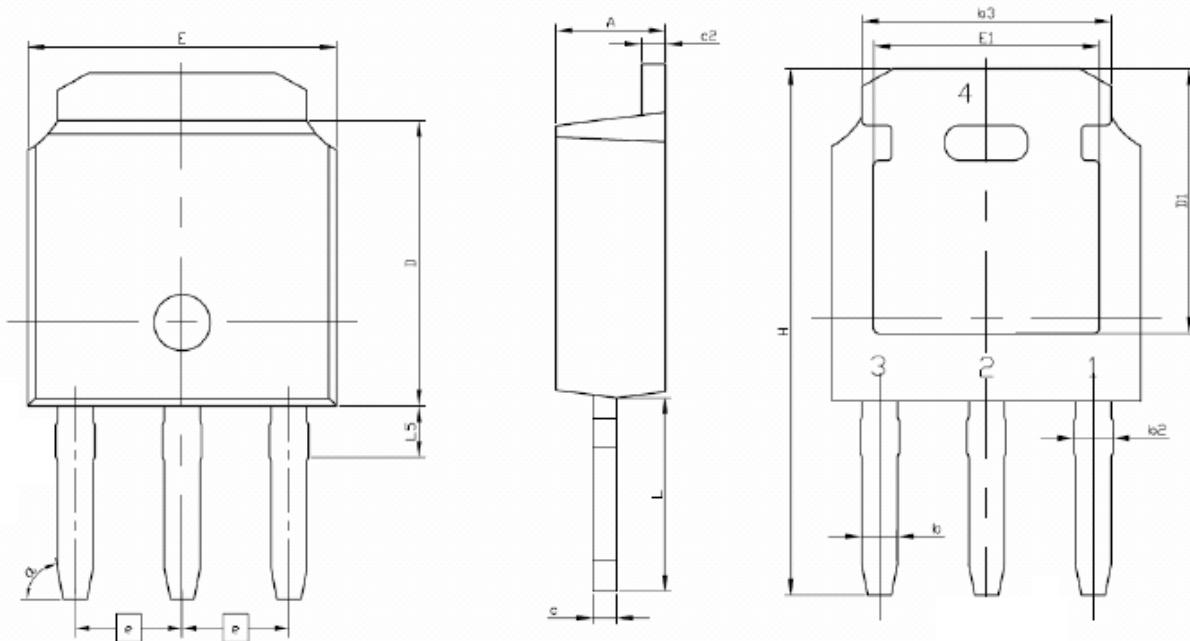


**Fig.12 Maximum Drain Current vs. Case Temperature**

## Physical Dimension

### TO-251-VS (IPAK-VS)

Dimensions are in millimeters, unless otherwise specified



Symbol	MILLIMETERS	
	Minimum	Maximum
A	2.18	2.39
b	0.64	0.89
b2	0.76	1.14
b3	4.95	5.46
c	0.40	0.61
c2	0.40	0.61
D	5.97	6.223
D1	5.10	-
e	2.286 BSC	
E	6.35	6.73
E1	4.32	-
H	10.26	11.45
L	3.98	4.28
L5	-	1.23

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